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**Question Paper Code : 31373**

B.E./B.Tech. DEGREE EXAMINATION, NOVEMBER/DECEMBER 2013.

Sixth Semester

Electronics and Communication Engineering

EC 2354/EC 64/10144 EC 704 – VLSI DESIGN

(Regulation 2008/2010)

(Common to PTEC 2354 – VLSI Design for B.E.(Part-Time) Fifth Semester –  
Electronics and Communication Engineering – Regulation 2009)

Time : Three hours

Maximum : 100 marks

Answer ALL questions.

PART A — (10 × 2 = 20 marks)

1. Compare CMOS and BiCMOS technology.
2. Draw the DC transfer characteristics of CMOS inverter.
3. Define power dissipation.
4. Define scaling. Mention the types of scaling.
5. Implement a 2:1 Multiplexer using pass transistor.
6. Design a 1-bit dynamic register using pass transistor.
7. What is the need for testing?
8. What is the principle behind logic verification?
9. Differentiate blocking and non-blocking assignments.
10. Mention the possible values which are allowed in Verilog HDL.

PART B — (5 × 16 = 80 marks)

11. (a) Explain the electrical properties of MOS transistor in detail.

Or

- (b) Derive an expression for  $V_{in}$  of a CMOS inverter to achieve the condition  $V_{in} = V_{out}$ . What should be the relation for  $\beta_n = \beta_p$ .

12. (a) Derive an expression for the rise time, fall time and propagation delay of a CMOS inverter.

Or

- (b) Explain the various ways to minimize the static and dynamic power dissipation.
13. (a) (i) Implement  $Y = (A + B)(C + D)$  using the standard CMOS logic. (8)

- (ii) Implement NAND gate using pseudo-nMOS logic. (8)

Or

- (b) (i) Implement D-flip-flop using transmission gate. (8)
- (ii) Implement a 2-bit non-inverting dynamic shift register using pass transistor logic. (8)

14. (a) Describe in detail, the various manufacturing test in CMOS testing.

Or

- (b) Explain in detail boundary scan testing.
15. (a) Write a Verilog HDL for an 8-bit Ripple Carry Adder using structural model.

Or

- (b) Write a Verilog HDL for a positive edge-triggered D-flip-flop. Using that implement an 8-bit shift register in structural model.